L Number	Hits	Search Text	DB	Time stamp
1	3817	((257/355-358) or (257/360-363) or (361/56,111)).CCLS.	USPAT;	2003/11/19 15:02
			US-PGPUB	
2	171	(((257/173,355-358,360-363) or (361/56,111)).CCLS.) and @pd > "20030619"	USPAT;	2003/11/19 15:05
			US-PGPUB	
3	107	((((257/173,355-358,360-363) or (361/56,111)).CCLS.) and @pd > "20030619") and	USPAT;	2003/11/19 15:06
		(esd electrostatic adj discharge)	US-PGPUB	
4	3	(reverse adj breakdown) and (breakdown near3 gate adj (oxide insulator)) and @pd >	USPAT;	2003/11/19 15:06
		"20030619"	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	•
5	79	reverse adj breakdown and @pd > "20030619"	USPAT;	2003/11/19 15:07
			US-PGPUB	
6	369	protection with diode and @pd > "20030619"	USPAT;	2003/11/19 15:07
			US-PGPUB	
7	77	breakdown near3 gate adj (oxide insulator) and @pd > "20030619"	USPAT;	2003/11/19 15:07
	_		US-PGPUB	
8	2	core adj region and I/O adj region and @pd > "20030619"	USPAT;	2003/11/19 15:08
			US-PGPUB	
9	92	protection with diode and cmos and @pd > "20030619"	USPAT;	2003/11/19 15:09
			US-PGPUB	
10	183	input adj pad and @pd > "20030619"	USPAT;	2003/11/19 15:08
			US-PGPUB	
11	14	((reverse adj breakdown) and input) and (protection with diode) and @pd >	USPAT;	2003/11/19 15:09
		"20030619"	US-PGPUB	
12	1	(protection with diode and cmos) and core adj region	USPAT;	2003/11/19 15:09
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
13	107	(((((257/173,355-358,360-363) or (361/56,111)).CCLS.) and @pd > "20030113") and	USPAT;	2003/11/19 15:10
		(esd electrostatic adj discharge)) and @pd > "20030619"	US-PGPUB	